

PO1014

## **Metal nitride thin films synthesized by reactive magnetron sputtering for supercapacitor applications**

Saïd Bouhtiyya<sup>1</sup>, Raul Lucio Porto<sup>2</sup>, Thierry Brousse<sup>2</sup>, Jean-François Pierson<sup>1</sup>, Fabien Capon<sup>1</sup>

<sup>1</sup>Institut Jean Lamour, Nancy, France <sup>2</sup>LGMPA, Nantes, France

said.bouhtiyya@ijl.nancy-universite.fr

Electrochemical capacitors (ECs), so called “supercapacitors” are high power density devices suitable for applications needing peak loads [1]. Most of the commercially available supercapacitors are using carbon materials as electrodes. This class of ECs is named “electrochemical double layer capacitors” with a capacity limited to  $\sim 250 \text{ F.g}^{-1}$  due the absence of surface redox reactions. A new class of ECs have been developed to overcome the low volumetric capacitance, named “pseudo-capacitors” in which the stored charge arise from charge transfer at the surface of the active material. Common materials used as electrodes are metal oxides such as  $\text{RuO}_2$ ,  $\text{MnO}_2$ . Besides these electrodes have been widely studied, metal nitrides have received sparse attention. Recently, VN has demonstrated impressive capacitance around  $1340 \text{ F.g}^{-1}$  at  $2 \text{ mV.s}^{-1}$  [2].

In this communication, we propose to study structural and electrochemical properties of binary metal nitrides elaborated by means of reactive ( $\text{Ar-N}_2$  atmospheres) magnetron sputtering. The use of thin films enables the study of the intrinsic properties of the materials without the use of binder neither conductive additives. The structure of the films was studied by X-ray diffraction and their morphology was observed by scanning and transmission electron microscopy. The electrochemical properties were determined by cyclic voltammetry in KOH electrolyte. Despite good electronic conductivity, poor capacitance values are measured for iron and copper nitrides while RuN, MnN, CrN, TiN and VN are the most promising, with up to  $300 \text{ F.cm}^{-3}$  (at  $100 \text{ mV.s}^{-1}$  scan rate) measured for columnar VN dense thin film.

[1] Simon, P.; Kumta, Gogotsi, Y. *Materials for Electrochemical Capacitors*, *Nature Materials*, (2008), 7, 845-854.

[2] Choi et al., *Adv. Mater.* 18 (2006) 1178

### **Keywords**

Supercapacitors

Pseudo-capacitors

Thin films

Metal nitrides

Magnetron sputtering